IN THE CLAIMS:

Please amend the claims as set forth below in marked-up form. In accordance with the revised amendment format, a clean copy of the claims has been omitted.

1. (Currently Amended) A method of determining a defect-free or ~~defect~~ defective semiconductor integrated circuit, comprising:

a first measurement step for measuring a quiescent power supply current (QPSC) of a first semiconductor integrated circuit (IC)~~,~~ a plurality of times in a predetermined interval after ~~stop of the~~ operation of the first IC has stopped;

a first data calculation step for calculating a first feature data indicating a feature(s) of the measured QPSCs of the first IC;

a second measurement step for measuring a QPSC of a second semiconductor IC~~,~~ a plurality of times in the same condition ~~to~~ as that of the first IC after ~~stop of the~~ operation of the second IC has stopped;

a second data calculation step for calculating a second feature data indicating a feature(s) of the measured QPSCs of the second IC; and

a comparison and determination step for comparing a ~~resemble~~ resemblance between the first feature data and the second feature data, and determining the first and second ICs as defect-free ICs when the ~~resemble~~ resemblance is high or the first and second ICs as ~~defect~~ defective ICs when the ~~resemble~~ resemblance is low.

2. (Original) A method according to claim 1, wherein the first and second ICs are formed on the same semiconductor wafer.

3. (Original) A method according to claim 2, wherein the IC comprises a complementary metal oxide semiconductor (CMOS) IC.

4. (Currently Amended) A method according to claim 1, wherein

one of the first and second ICs is decided as a reference IC~~,~~;

the second measurement step and the second calculation step are carried out for ~~other~~ another semiconductor IC as the second IC~~,~~; and

in the comparison and determination step, the second IC is determined as a defect-free IC when the ~~resemble~~ resemblance is high, or as a ~~defect~~ defective IC when the ~~resemble~~ resemblance is low.

5. (Currently Amended) A method according to claim 1, wherein

in the first data calculation step, a first average QPSC of the measured QPSCs of the first IC and a first plurality of QPSC deviations of the measured QPSCs of the first IC, which are ~~(~~the measured QPSCs of the first IC ~~-~~minus the first average~~)~~, are calculated~~,~~;

in the second data calculation step, a second average QPSC of the measured QPSCs of the second IC and a second plurality of QPSC deviations of the measured QPSCs of the second IC, which are ~~(~~the measured QPSCs of the second IC~~-~~ minus the second average~~)~~, are calculated~~,~~; and